

Alkali treatment for single-stage co-evaporated thin $\text{CuIn}_{0.7}\text{Ga}_{0.3}\text{Se}_2$
solar cells

Peer-reviewed author version

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Abstract: KF and NaF treatments were done for single-stage co-evaporated CuIn_{0.7}Ga_{0.3}Se₂. The absorber layers were grown on a substrate with an alkali barrier layer and NaF was either added before or after absorber layer growth. No differences were found on the device performance amongst the procedures to add Na. This is expected if the single-stage process does not have a copper rich stage or a Ga gradient, which is likely since there was no change of the elemental fluxes during absorber layer growth and no Ga profile was measured. KF was added by post-deposition only. Current-voltage characteristics were measured and net doping concentrations were determined from capacitance-voltage measurements (CV). We see an improvement of the open-circuit voltage (Voc) with increasing KF amount, and a marginal increase of the fill factor. CV measurements showed increasing net acceptor concentration with increasing KF amount. Time resolved photoluminescence (PL) showed an increased decay time for KF treated cells and the PL peak shape changed. Without KF treatment the PL peak is symmetric, after KF treatment a further peak appears at higher energy in the PL spectrum. This higher energy peak increases in intensity with increasing KF concentration. The same effects were seen in a sample without Na, but here the Voc was limited due to large tailing. Hence both Na and K are required for good cell efficiencies.

Dear Editor,

Hereby I would like to submit the revised paper 'Alkali treatment for single-stage thin CIGS'. It was presented as an oral presentation at E-MRS in session VIII.1.

We have commented on the suggestions the reviewers had. Our comments to the reviewers can be found in the response to reviewers and are written in red. Parts from the manuscript that are adapted due to the reviewers' comments are copied below the corresponding comment and highlighted. We also went thoroughly through the paper and clarified and adapted the English language where required. In the manuscript, the parts that are changed, either because of the reviewer comments or our own revision, are written in red.

We hope that the manuscript is now suitable for publication in the E-MRS issue of thin solid films.

Thank you in advance for your time and effort and we are waiting for your response concerning this manuscript.

Kind regards,

The authors

Referee 1

The manuscript has been improved. Nevertheless some revisions have still to be done. Especially English grammar has to be optimized. Further the interpretation of PL data has to be revised (see below).

Thank you for the suggestions. Below you can find our response in red and changes in the text are highlighted.

Page 2, line 3: Please replace "using" by "to use"
done

Page 2, line 5: Please delete "and reduces the ...[3]." as this statement is not given in references 2 and 3. Further this statement is not clear and misunderstanding.

The cited papers refer to the statement that alkali diffuse, which is shown very clearly in the papers. The reduction of alkali follows logically from the idea that a thinner CIGS layer needs less alkali in absolute amount, and hence less alkali can diffuse to the interfaces. I have adapted text as follows:

while thinner cells lead to less material usage and thereby reduces the absolute amount of alkali metals.

Page 2, line 14: Please replace "K" by "KF"
done

Page 2, last line: Please replace "no gradients are expected" by "no gradients in elemental concentration profiles were measured by GDOES (not shown)."
done

Page 3, Results, line 8: Please replace "post treatment" by "post deposition treatment"
done

Page 3, results, line 9: Please add "...5x5 cm² with a cell area of 0.5cm²." at the end of the sentence.
The cell area is mentioned in the sentence before.

Page 4, Figure 1 caption: Please add at the end "...higher Jsc which is caused by the lower net doping."
done

Page 4, section 3.2 KF PDT, line 3: Please add the following sentence after "The Na was added by pre-deposition.": "The cells without KF PDT are annealed and further processed in the same way as the KF treated cells."
done

Page 5, line 6: Please replace "than the cells" by "than for the cells"

done

Page 5, line 12: Please add "...attributed to the alkali treatments and are not caused by variations in the Ga content."

done

Page 5, line 16: Please replace "does imply" by "implies"

done

Legend of Figure 3: Please replace "0.2M w/o NaF" by "0.2M KF w/o NaF"

done

Figure 4: Please use colors for "0.2 M KF" and "0.1M KF" which can be better separated from each other like red and green (instead of brown and green)

Colors of the different samples are adapted.

Legend of Figure 4: Please replace "0.2 M" by "0.2M KF" and "0.1 M" by "0.1M KF"

Done

Page 6, second last line: Please replace "absorbers" by "absorber"

done

Page 7, line 6: Please replace "w/o KF" by "w/o NaF"

done

Page 7, line 10: Please replace "while w/o KF..." by "while w/o KF the PL peak is slightly assymetric."

This is not true, the peak is rather symmetric, otherwise it couldn't be fitted with 1 Gaussian. The text concerning the fitting is adapted as follows:

The spectra are fitted with Gaussian shaped peak profiles and the peak maxima are given in table 2. We clearly see again two distinguishable peaks for the KF treated cells, while for the sample w/o KF the spectra can be fitted with one broad distribution. It seems that the band edge emission for the sample w/o KF is indistinguishable from the tail emission. After KF treatment the tail emission might be reduced, leading to the observed disentanglement of the band edge and tail states emission peaks.

Figure 6: Please fit the PL spectrum of the sample w/o KF also with 2 peaks located at 1.15 and 1.22 eV, as the peak is assymetric and shows a shoulder at the right side which can be attributed to the "green" peak. Please add the peak data of the new it into table 2 for the sample "w/o KF".

Done.

I have doubts concerning the interpretation that the peak at 1.15 eV is attributed to tail states. Tail states should not lead to a Gaussian shaped peak profile. Could it be that the two peaks can be attributed to emission from E_{gap} and emission from donor acceptor transition? The peak values and the peak distance of 63-78 eV very well fits to the data of Niklas Rega (PhD thesis, Free University Berlin, 2004, PL at epitaxial CIGS layers). Please consult an PL expert (for example Prof. Susanne Siebentritt, Uni Luxembourg) to discuss and interpret the results correctly. I do not believe in the interpretation of "tail states".

Thank you for this contribution. I am quite familiar with the photoluminescence work done in Luxembourg, as I worked closely with Prof Siebentritts group for 3 years. I also have had discussions with some of my former colleagues. But please notice that their work is based on highly efficient thick 3-stage CIGS absorber layers, while I have thin 1-stage absorber layers. This by itself is already unexplored. For instance, when I compare the PL spectra of my 1-stage sample with the PL spectra of a 3-stage sample with same composition and thickness the main peak of the 1-stage sample is at lower energy and broadened.

Considering the donor-acceptor transitions: The PL spectra is taken at room temperature, so there are no donor-acceptor transitions and the emission should come from the band edge for ideal material (see also ref 15 on what transitions are measured at which temperature). This is not what we observe for our 1-stage sample and deviates in many ways from 3-stage CIGS. The photoluminescence spectra of the 1-stage sample are thus far from ideal.

About the Gaussian peak shape: Please notice that emission from below the band gap can be modelled with different models for sub band gap absorption (see for instance Katahara, 2014). The simplest form of sub band gap emission is gaussian shaped. This can lead to -but not necessarily- a gaussian shaped peak. Similar observations, i.e. peak maximum below the band gap and a gaussian peak shape are also visible in kesterite samples where the emission is considered to come from tail states (see for instance the room temperature PL of Tat Ming Ng, J. Mater. Chem. A ,2017). Altogether, we do think emission from tail states is a reasonable explanation for the observed PL spectra of our 1-stage samples.

Page 8, line 8: Please replace "alkali is found" by "alkali metals accumulate"

done

Page 8, line 9: Please replace "junctions" by "junction"

done

Page 9, line 2: Please replace "performed pre-deposition or post deposition" by "performed by pre-deposition or post deposition treatment"

done

Page 9, line 4: Please replace "attribute" by "attributed"

done

Page 9, line 6: Please replace "done post" by "done by post"

done

Page 9, line 9: Please replace "CV" by "CV measurements"

done

Page 9, line 10: Please replace "had no Na" by "without any Na pre-treatment"

done

Referee 2

Since the previous review stage, the authors improved the quality of the manuscript and implemented a number of suggestions received. However, the language used is still below expectations for a peer-reviewed publication. We recommend a careful reading of the manuscript. In addition, some discussions and interpretation remain confusing, as detailed below. Therefore, we recommend accepting the manuscript with minor revisions.

Thank you for the comments and suggestions. You can find our response in red and adapted text highlighted.

A list of requested changes is provided below:

Experimental details:

- "The Si(O,N) layer" layer thickness.

It was already given (~140 nm)

- "KF treatments were always done after the growth of the CIGS absorber layers." Please specify how the treatment was applied, for example, "using the same spin-coating process as for NaF".

done

- Please provide a description for the EQE setup. The manuscript reports values extracted from EQE data, and other results are discussed thanks to these values.

Following information is added:

External quantum efficiency (EQE) measurements were performed with a Bentham PVE300 photovoltaic QE system. The resolution was set to 10 nm and band gaps were determined from τ_{auc} plots.

Results

- "This is likely due to the lack of a copper rich phase during growth". More relevant would be "This is likely due to the lack of a copper rich phase and corresponding grain growth during deposition process"

done

- "The thickness was 0.47 μm for the sample w/o KF and 0.1 M KF and 0.43 μm for 0.2 M KF and 0.2 M w/o NaF." The sentence is confusing. For example, "The thickness was 0.47 μm for the samples w/o KF and 0.1 M KF, and 0.43 μm for samples 0.2 M KF and 0.2 M w/o NaF."

done

- The few lines starting from sentence "Secondly, we find that the doping profile is dependent on the frequency" until the end of the paragraph must be reworked.

- I would interpret all shown CV profiles to indicate full depletion of the absorbers, for KF treated cells and for every frequencies. If the author maintain their claim, I would expect a discussion about how an absorber could be depleted using a frequency and not using another.

- From my understanding of the discussion, several possible explanations are provided and are listed below. I request the authors to reformulate the paragraph to provide clarity to the reader. a) formation of a defect inside bandgap upon KF treatment. b) presence of interface defects at one of the interfaces. c) presence of a barrier at one of the interfaces. d) the increased doping in KF treated cells makes an preexisting de-fect level to cross Fermi level.

The main reason I think that after KF treatment the cells are not completely depleted is because the SCR region is below 500 nm for some frequencies. This could be questioned, considering how the position x is determined, and the cells might be depleted as well. We are still looking into the interpretation of the observed measurement and decided to keep it open for now. I did suggest a few interpretations on what causes shifts in CV measurements and added references of frequency-dependent CV measurement on alkali treated CIGS. The text is now as follows:

Secondly, we find that the doping profile is dependent on the frequency for the KF treated cells. The frequency dependence of the capacitance of thin film solar cells is widely explored and has led to a variety of explanations. At first, the different frequencies may probe different defects within the band gap, which results in an increased capacitance. The observed shift is then interpreted as a newly formed defect due to the KF PDT. More recently though, the frequency dependent CV measurements of alkali treated CIGS are interpreted as a transport barrier at the front [13] or deep defects at the pn junction [14]. To conclude on what causes the measured shift with the KF treatment, more advanced characterization like low temperature CV and JV measurements are required.

- 2 sentences starting with "At room temperature PL comes from band to band". Please rephrase with something similar as "At room temperature the PL peak maximum is expected just above the bandgap energy [14]. However, in disordered semiconductors significant emission can also come from the tail states."

done

- "For clarity the spectra are fitted with". Please remove "For clarity"

done

- "to the much smaller grainsize due to the single-stage process." Please rephrase as "to the small grain size and the presence of extended defects due to the single-stage process." A reference to [6] or to [Mainz <http://dx.doi.org/10.1039/c6ee00402d>] may be provided here.

Thank you for this reference. I was not aware of this paper and it is very useful.

- "The decay curves of the cells are shown in figure 7 and have significantly increased with KF treatment in general." -> "TRPL transients cells are shown in figure 7. Decay times significantly increase with the explored KF treatments."

done

- "several concurrent recombination processes and depends on whether theirs is an electric field present" -> "several concurrent recombination or charge extraction processes and depends on the presence of an electric field."

Done

Note: Charge carriers extraction in TCO lead to shorter decays. Charge separation by an electric field leads a very fast initial decay followed by a much slower decay. The exact transients depends on the specifics.

Note: possibly the decay of KF treated cells are limited by the extraction of electrons in the TCO layer. Measurement of absorbers covered with only CdS could provide more insights.

Thank you for these useful comments.

In general, the TRPL transients do not differ much between solar cells and absorber layers for the 1 stage samples. Extracted lifetimes are in the order of 2 max 3 ns. Though, since decay time due to charge separation is beyond the detection limit of our setup, we adapted the text as follows:

Decay time is the inverse of the sum of several concurrent recombination or charge extraction processes and depends on the presence of an electric field. Though, the latter is beyond the detection limit of the set up. Hence, improvements are observed if the limiting decay time is increased or if there are no charge extraction processes. Since we don't expect significant changes for the charge extraction processes, we attribute the increase in lifetime to reduced recombination.

Table 2

- Column labels: please replace "Red" and "Green" with "Low energy peak" and "High energy peak".

done

Highlights

Thin ~ 500 nm CIGS solar cells were prepared by 1-stage co-evaporation

Na and K alkali treatments were investigated pre- and post-deposition of the absorber layer

KF treatment is performed in N₂ atmosphere

Alkali treatment for single-stage co-evaporated thin $\text{CuIn}_{0.7}\text{Ga}_{0.3}\text{Se}_2$ solar cells

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Abstract

KF and NaF treatments were done for single-stage co-evaporated $\text{CuIn}_{0.7}\text{Ga}_{0.3}\text{Se}_2$. The absorber layers were grown on a substrate with an alkali barrier layer and NaF was either added before or after absorber layer growth. No differences were found on the device performance amongst the procedures to add Na. This is expected if the single-stage process does not have a copper rich stage or a Ga gradient, which is likely since there was no change of the elemental fluxes during absorber layer growth **and no Ga profile was measured**. KF was added by post-deposition only. Current-voltage characteristics were measured and net doping concentrations were determined from capacitance-voltage measurements (CV). We see an improvement of the open-circuit voltage (V_{oc}) with increasing KF amount, and a marginal increase of the fill factor. CV measurements showed increasing net acceptor concentration with increasing KF amount. Time resolved photoluminescence (PL) showed an increased decay time for KF treated cells and the PL peak shape changed. Without KF treatment the PL peak is symmetric, after KF treatment a further peak appears at higher energy in the PL spectrum. This higher energy peak increases in intensity with increasing KF concentration. The same effects were seen in a sample without Na, but here the V_{oc} was limited due to large tailing. Hence both Na and K are required for good cell efficiencies.

1. Introduction

Thin film $\text{CuIn}_{0.7}\text{Ga}_{0.3}\text{Se}_2$ (CIGS) solar cells have reached efficiencies close to 23% [1] by using several alkali treatments. Despite these high laboratory efficiencies CIGS is still lagging on module efficiencies, mainly due to the complex 3-stage co-evaporation process required to reach these high efficiencies. The 3-stage co-evaporation process is an advanced process that involves a copper rich stage and a Ga gradient. While this leads to high efficiency cells it also makes the process complex, more difficult to upscale and increases the cost of CIGS modules due to the high amount of material required. There are several ways to improve the cost performance, like increasing the efficiency and/or reducing processing costs. We aim to make CIGS thinner (~ 500 nm) and **to use** a single-stage process to make CIGS more cost effective. The single-stage co-evaporation process increases the production speed, while thinner cells lead to less material usage and **thereby** reduces the **absolute** amount of alkali metals. While alkali metals are required to reach high efficiencies, they cause degradation on the long term due to diffusion towards the interfaces [2,3] and hence the amount needs to be carefully controlled. Here we investigate the effect of Na and K on the performance of thin single-stage CIGS solar cells. The effect of Na is broad and widely investigated. It is known to increase the net acceptor concentration [4,5], it affects the crystal size during growth [6] and the diffusion of Ga towards the back contact [7]. The latter two effects are attributed to a copper rich phase during growth and the presence of a Ga gradient. In these cases, it also matters whether the Na supply is realized by post or pre-deposition. The effects of the **KF** post-deposition treatment (PDT) are still under discussion, but it also increases the net acceptor concentration [8]. However, it mostly seems to modify the CIGS/CdS interface positively [9–11]. Here, KF treatment is performed by post-deposition treatment only.

For our single-stage samples we investigated the effect of the different alkali treatments on the device performance. At first, we investigate the effect of Na addition before and after absorber layer growth. There were no significant differences between the different Na treatments on the electrical performance of solar cells found. A reference sample without any Na was made and we indeed see an increase in net acceptor concentration with Na compared to the sample w/o Na. Based on the Na experiments, we spin-coated one layer of NaF before CIGS growth, since this eliminated a separate PDT step. The KF treatments were done post-deposition and samples with only Na were used as reference. With the KF treatment large improvements were found for the open-circuit voltage (V_{oc}), the net acceptor concentration and the decay time. The photoluminescence (PL) spectra revealed an additional peak at higher energy.

2. Experimental details

CIGS layers are deposited at 550 °C on Mo/Si(O,N)/soda lime glass substrates. The Si(O,N) layer is ~ 140 nm and functions as an alkali barrier layer. That way, the alkali concentrations are controlled by pre- and post-deposition treatments only. The CIGS layers are deposited by single-stage co-evaporation. The crucible temperatures are set in such a way that the evaporation rate of each element to the substrate immediately leads to the required composition. When the evaporation rates are stabilized the shutter is opened for 7.30 minutes, which results in a thickness of about 0.5 μm . Exact composition and thickness were measured with XRF. No gradients in elemental concentration profiles were measured by GDOES (not shown). This is in contrast to other single-stage processes, where Ga profiles were added on purpose by changing the evaporation rates to the substrate [12]. Na was added by dissolving NaF in deionized water and spin-coating a 0.2 M NaF solution with a speed of 3000 rpm and acceleration of 5000 rpm/s for 10 s in total. This was either done on a Mo substrate or after CIGS deposition. KF treatments were always done after

the growth of the CIGS absorber layers using the same spin-coating process as for NaF. The post-deposition samples were annealed in a N₂ atmosphere for 20 minutes at 400 °C. To avoid degradation of the surface, the CIGS absorber layers were directly capped with CdS by chemical bath deposition. Solar cells were prepared by sputtering i-ZnO/Al:ZnO window layers and finished with Ni/Al grids. PL and time-resolved PL (TRPL) were measured with a fluorescence spectrometer from Hamamatsu at room temperature. As excitation source a 15 kHz laser with a wavelength of 532 nm was used. The power was 1 mW and the spot size ~ 30 mm². The solar cells were characterized by a homebuilt current-voltage (JV) and capacitance-voltage (CV) set up. The frequency varied from 1 kHz to 1 MHz. External quantum efficiency (EQE) measurements were performed with a Bentham PVE300 photovoltaic QE system. The resolution was set to 10 nm and band gaps were determined from τ_{auc} plots.

3.Results

3.1 NaF treatment of single-stage co-evaporated CuIn_{0.7}Ga_{0.3}Se₂

Absorber layers were prepared with a Cu/(In + Ga) ratio (GGI) of 0.8 and Ga/(Ga + In) ratio (CGI) of 0.27. The thickness varied from 0.39 to 0.49 μm. The absorber layers underwent different NaF treatments and were directly finished into solar cells. The different Na treatments (thickness) were as follows: without (w/o) Na (0.49 μm), pre-NaF deposition 1 layer (0.39 μm), post-NaF deposition 1 layer (0.49 μm), post-NaF deposition 2 layers (0.49 μm) and pre-NaF deposition 1 layer but undergoing the post treatment anneal without NaF deposition (0.47 μm). The latter one is for reference of the post treatment anneal itself. The solar cells have an area of 0.5 cm² and were mechanically scribed. The number of cells that are measured varied between 5 to 7 on 5x5 cm² samples. The results of the JV measurements are presented in Figure 1. We find no significant differences in V_{oc} and fill factor (FF) between

the different Na treatments. The differences in short circuit current density (J_{sc}) can directly be attributed to the different absorber layer thicknesses. The findings are in contrast with the 3-stage process where post-deposition treatment is preferred. This is likely due to the lack of a copper rich phase and corresponding grain growth during the deposition process. Also, increasing the amount of Na by PDT does not affect the final performance significantly. The only sample showing significant different V_{oc} , J_{sc} and FF is the one without any Na treatment. It has a lower V_{oc} and FF but higher J_{sc} . This can be attributed to lower apparent doping concentration. Doping profiles were determined from CV measurements at different frequencies and the results are presented in Figure 2. We find a 3 times lower doping for the cells without Na, compared to the solar cell that has 1 layer NaF PDT. The doping profile of this latter solar cell is representative for all Na treated solar cells. The effect of the post anneal itself is also shown in figure 1 under the name 'pre + post anneal'. We again find no significant differences and we conclude that the anneal treatment itself does not influence the solar cell properties significantly.

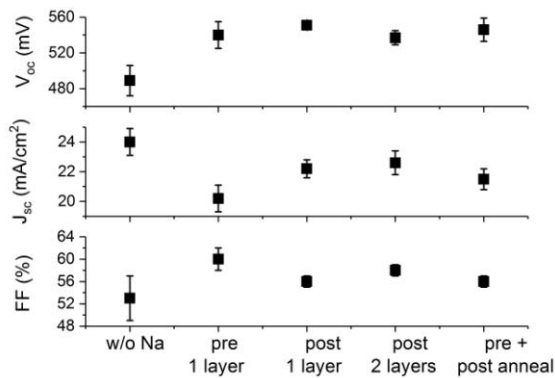


Figure 1 Average values of V_{oc} , J_{sc} and FF for different Na treatments. No significant difference between the different Na treatments is observed. The cells without Na gave a lower V_{oc} and FF and higher J_{sc} which is caused by the lower net doping.

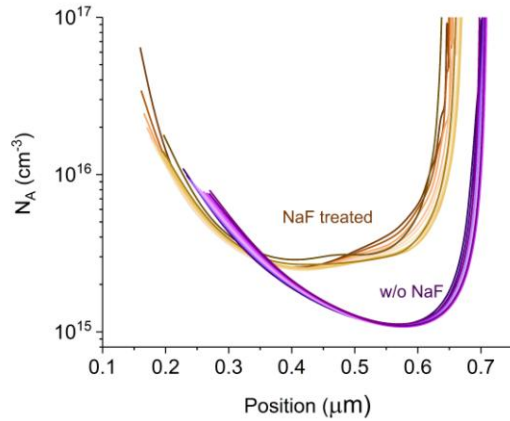


Figure 2 Net doping (N_A) extracted from capacitance-voltage measurements of absorbers with 1 layer NaF PDT and without NaF. The different shades of color represent the different frequencies.

3.2 KF post deposition treatment

KF post deposition treatments were done by spin-coating 0.1 M and 0.2 M KF solutions on CIGS absorbers followed by annealing the samples at 400 °C for 20 min in N₂ atmosphere. Spinning parameters are the same as those used for NaF. The Na was added by pre-deposition. As reference a sample without KF was annealed as well and further processed in the same way as the KF treated cells. The CGI of the samples was between 0.86 - 0.9 and the GGI was 0.3. The thickness was 0.47 μm for the samples w/o KF and 0.1 M KF and 0.43 μm for the samples 0.2 M KF and 0.2 M KF w/o NaF. In figure 3 average values for V_{oc} , J_{sc} and FF are presented. We see a significant increase of the V_{oc} from ~ 550 mV to 610 mV for the 0.2 M KF treated cells. The 0.1 M KF treated cells only show a marginal increase. The FF is on average slightly higher for the KF treated cells as well. At last KF treatment (0.2 M) was done on an absorber without any Na pre-treatment. Here, the V_{oc} is slightly higher than for the cells without KF (and only Na pre-treatment) and the FF the highest. The same trend was observed when comparing pure NaF PDT with pure KF PDT [10]. The J_{sc} varied between 20 and 22 mA/cm². The lower and higher values are

corresponding with the different thicknesses of the absorber layers. From EQE measurements band gaps between 1.18 and 1.20 eV were determined (not shown here), thus the V_{oc} improvements can be attributed to the alkali treatments and are not caused by variations in the Ga content. In table 1, values for the highest V_{oc} , corresponding FF and doping determined from CV measurements are given. Doping profiles of the KF treated samples and the reference are presented in figure 4. The KF treated cells without Na pre-treatment had the same profile as the 0.2 M KF treated cells with Na pre-treatment but were left out for clarity of the figure. This implies that the doping is determined by the KF treatment. When we look at the different doping profiles, we observe significant differences between the KF treated and non-KF-treated samples. Firstly, the acceptor concentration is increasing with increasing KF amount. This by itself could lead to the observed V_{oc} improvement, like we measured for Na/no Na cells. However, the cells without Na have a significant lower V_{oc} , but the same doping level. This excludes V_{oc} improvements due to increase in doping only. Secondly, we find that the doping profile is dependent on the frequency for the KF treated cells. The frequency dependence of the capacitance of thin film solar cells is widely explored and has led to a variety of explanations. At first, the different frequencies may probe different defects within the band gap, which results in an increased capacitance. The observed shift is then interpreted as a newly formed defect due to the KF PDT. More recently though, the frequency dependent CV measurements of alkali treated CIGS are interpreted as a transport barrier at the front [13] or deep defects at the pn junction [14]. To conclude on what causes the measured shift with the KF treatment, more advanced characterization like low temperature CV and JV measurements are required.

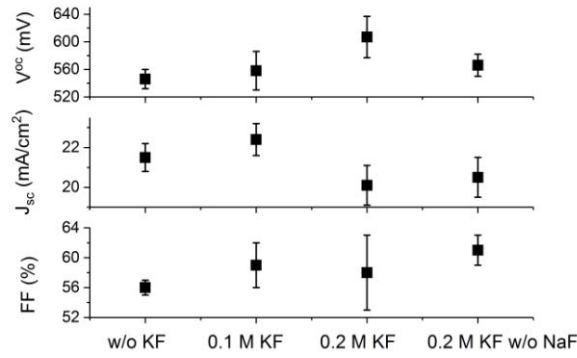


Figure 3 Average values of V_{oc} , J_{sc} and FF for different KF treatments. Na was supplied by pre-treatment.

Table 1 Parameters of the best cells for the different KF treatments shown in figure 3.

Na supply	K supply	Highest V_{oc} (mV)	Highest FF (%)	Doping (10^{16} cm^{-3})
pre	w/o	564	57	0.2
pre	0.1 M	590	62	0.3-0.5
pre	0.2 M	641	64	0.4-0.7
w/o	0.2 M	586	64	0.4-0.7

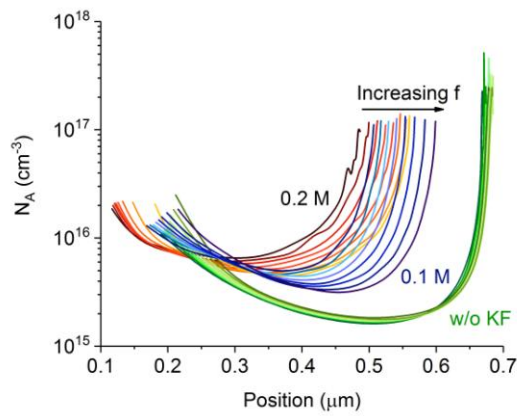


Figure 4 Net doping extracted from capacitance-voltage measurements at different frequencies for absorbers with(out) KF treatment. After KF treatment the net

acceptor doping has increased and the cells have depletion width dependency on the frequency.

3.3 Photoluminescence

Room temperature PL and TRPL were done on absorber layers capped with CdS and finished solar cells. *At room temperature the PL peak maximum is expected just above the bandgap energy [15]. However, in disordered semiconductors significant emission can also come from the tail states.* Figure 5 shows the PL spectra of the absorber layers capped with CdS with and w/o Na after 0.2 M KF treatment. The measurement conditions were the same. *The individual spectra are fitted with 2 Gaussian shaped peaks and the values of the fit are given in table 2. Both spectra are shown in the upper graph for comparison.* As we can see, there is a significant amount of emission below the band gap of ~ 1.2 eV (red peak), probably coming from tail states. *That our absorbers have large amount of tails can be attributed to the small grain size and the presence of extended defects due to the single-stage process [16].* The high energy peak (green peak) is likely coming from the band edge. A few differences between the two samples can be observed. At first, we find that the low energy peak of the sample without Na is broader than that of the sample with Na. Secondly, we observe that the emission intensity is lower for the sample w/o Na as well. This broadened low energy peak and lower intensity should reduce the V_{oc} . These absorber layers were further processed into the solar cells belonging to 0.2 M KF and 0.2 M KF w/o NaF and indeed a lower V_{oc} (~ 40 mV) was measured for the sample w/o NaF. The PL spectra of finished solar cells w/o KF, 0.1 M KF and 0.2 M KF *with Na pre-treatment are presented in figure 6.* There is a marginal difference in peak intensity for the solar cells (up to 1.2 times) and we show the normalized spectra. The spectra are fitted with Gaussian shaped peak profiles and the peak maxima are given in table 2. *We clearly see again two distinguishable peaks for the KF treated cells,*

while for the sample w/o KF the spectra can be fitted with one broad distribution. It seems that the band edge emission for the sample w/o KF is indistinguishable from the tail emission. After KF treatment the tail emission might be reduced, leading to the observed disentanglement of the band edge and tail states emission peaks.

Table 2 Peak maxima extracted from fit of PL spectra shown in figure 6 with Gaussian shaped peaks.

Sample	Low energy peak (eV)	FWHM (meV)	High energy peak (eV)	FWHM (meV)
0.2 M KF w NaF CIGS/CdS	1.11	73	1.20	104
0.2 M KF w/o NaF CIGS/CdS	1.10	125	1.21	80
w/o KF w NaF Solar cell	1.17	103	-	-
0.1 M KF w NaF Solar cell	1.16	82	1.22	77
0.2 M KF w NaF Solar cell	1.15	86	1.23	81

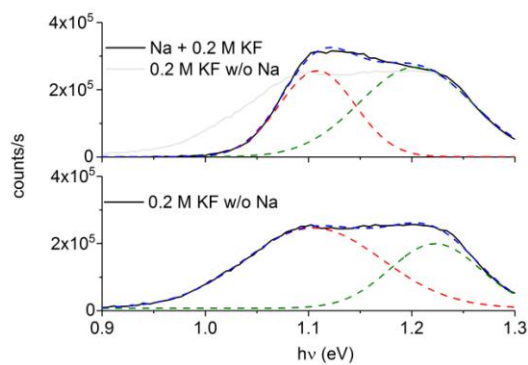


Figure 5 Photoluminescence spectra of absorber layers that underwent KF PDT with (upper graph) and without (lower graph) Na pre-treatment. The spectra are fitted with two Gaussian shaped peaks. For intensity and shape comparison, both spectra are plotted in the upper graph. The sample without Na has a lower intensity and a broader tail (red peak).

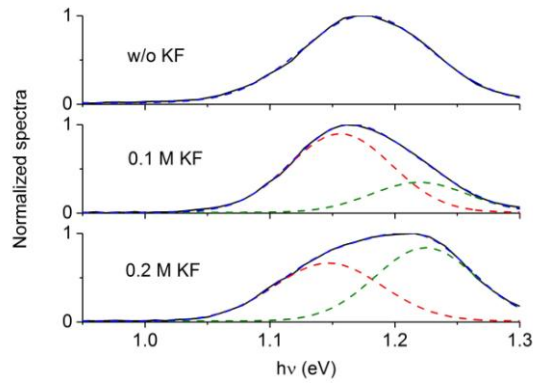


Figure 6 Room temperature photoluminescence spectra of finished solar cells. The spectra are fitted with Gaussian shaped peaks. Without KF treatment the PL spectra can be fitted with one broad Gaussian.

TRPL transients of the solar cells are shown in figure 7. Decay times significantly increase with the explored KF treatments. However, there is no relationship with the total amount of KF. Decay time is the inverse of the sum of several concurrent recombination or charge extraction processes and depends on the presence of an electric field. Though, the latter is beyond the detection limit of the set up. Hence, improvements are observed if the limiting decay time is increased or if there are no charge extraction processes. Since we don't expect significant changes for the charge extraction processes, we attribute the increase in lifetime to reduced recombination. At this stage it is hard to say whether the increase is due to reduced recombination in the bulk or at the interface. From literature we know that the CdS/CIGS interface improves with KF treatment and that the alkali metals accumulate at the pn junction and back contact [10,11]. This will change recombination rates at the interfaces which will affect the decay time for thin layers like ours. However, we also find changes in the bulk as we can conclude from the PL spectra and the doping profile. Hence, it is likely a combined effect and more experiments on both finished devices and the absorber layers are required to differentiate.

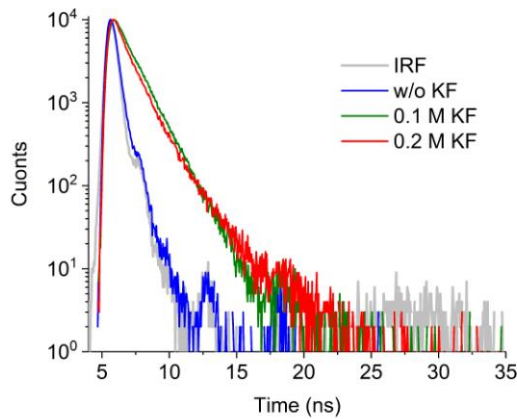


Figure 7 Room temperature time resolved photoluminescence of finished solar cells. The KF treated cells show a clear increase of decay time. The light grey curve is the instrumental response function (IRF).

4. Conclusion

We have investigated the effects of NaF and KF treatments on thin single-stage CIGS absorbers, either performed **by** pre-deposition or post-deposition **treatment** in N_2 atmosphere. We found that for the device performance it did not matter whether Na was added before or after absorber layer growth. This was attributed **d** to the constant elemental flux during CIGS growth that leads to the absence of a copper rich stage and a Ga gradient. KF treatment was done **by** post-deposition only and we found significant improvements in device performance for higher concentrations of KF. All KF treated cells showed similar changes in CV measurements, PL spectra and **TRPL transients**. The PL spectra revealed a second peak at higher energy and the TRPL an increased decay time. From CV measurement a higher net acceptor concentration was determined. One sample without Na underwent only KF treatment. It revealed the same features in the PL spectra and doping profile as the other KF treated samples, but the solar cells had a lower V_{oc} compared to the sample that had Na. The PL spectra revealed a broader tail for this sample, which likely limited the V_{oc} . It shows that both alkali metals are required to obtain good cell efficiencies.

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